

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant(s): MAMITSU et al.	Atty. Dkt.: 01-103-CON3
Serial No.: Unknown	Group Art Unit:
Filed: Concurrently herewith	Examiner:
Title: SEMICONDUCTOR DEVICE HAVING RADIATION STRUCTURE	

Commissioner for Patents  
Arlington, VA 22202

Date: November 4, 2003

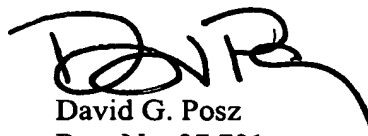
**INFORMATION DISCLOSURE STATEMENT**

Sir:

Pursuant to 37 C.F.R. §1.56, the reference(s) listed on the attached Form PTO-1449 is/are being submitted for consideration by the Examiner without any admission that it/they constitute(s) statutory prior art, or without any admission that it/they contain(s) subject matter that anticipates the invention or renders the invention obvious to a person of ordinary skill in the art.

The Examiner is requested to initial the attached PTO Form-1449 and to return a copy of same to the undersigned attorney as proof that the listed reference(s) has/have been considered and made of record.

Respectfully submitted,



David G. Posz  
Reg. No. 37,701

Posz & Bethards, PLC  
11250 Roger Bacon Drive, Suite 10  
Reston, VA 20190  
(703)707-9110 (phone)  
Customer No. 23400

## PATENT APPLICATION

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	APPLICANT	MAMITSU et al.	
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## REFERENCE DESIGNATION

## U.S. PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS
RP	5,708,299	Jan. 13, 1998	Teramae et al		
RP	6,072,240	June 6, 2000	Kimura et al		
RP	5,248,853	Sep. 28, 1993	Ishikawa et al		
RP	5,801,445	Sep. 1, 1998	Ishihara et al		
RP	5,229,646	Jul. 20, 1993	Tsumura		
RP	4,558,345	Dec. 10, 1985	Dwyer et al		
RP	4,546,374	Oct. 8, 1985	Olsen et al		
RP	4,984,061	Jan. 8, 1991	Matsumoto		
RP	5,481,137	Jan 2, 1996	Harada et al.		
RP	4,827,082	May 2, 1989	Horiuchi et al		
RP	4,538,170	Aug. 27, 1985	Yerman		

## FOREIGN PATENT DOCUMENTS

## TRANSLATION

DOCUMENT NUMBER	DATE	COUNTRY	NAME	CLASS	SUB CLASS	YES	NO
RP EP0660396	12/24/93	Europe					
RP EP0450980	4/05/91	Europe					
RP 6-291223	10/94	JAPAN					
RP 3-20067	01/91	JAPAN					
RP 2146174	11/85	GB					

## OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, etc.)

RP	Takamura, "Electronic Technology", pp. 56-59 (1999-5).
RP	Johnson et al., "Silicon Precipitate Nodule-Induced Failures of MOSFETS", ISTFA '91 (Nov. 11-15, 1991), pp. 161-165.
EXAMINER	DATE CONSIDERED
RP	8/11/05

## PATENT APPLICATION

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FORM PTO-1449	ATTY. DKT NO.	1-103-CON3	SER. NO.
	APPLICANT	MAMITSU et al.	
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## REFERENCE DESIGNATION

## U.S. PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS
<i>PS</i>	4,646,129	Feb. 24, 1987	Yerman et al		
<i>PS</i>	4,141,030	Feb. 20, 1979	Eisele et al		
<i>PS</i>	6,448,645	Sep. 10, 2002	Kimura		
<i>PS</i>	6,538,308	Mar. 25, 2003	Nakase		
<i>PS</i>	6,380,622	Apr. 30, 2002	Hirai		
<i>PS</i>	09/675,209	Filed Sept. 29, 2000	Suzuki		
<i>PS</i>	5,221,851	Jun. 22, 1993	Gobrecht et al.		

## FOREIGN PATENT DOCUMENTS

## TRANSLATION

	DOCUMENT NUMBER	DATE	COUNTRY	NAME	CLASS	SUB CLASS	YES	NO
<i>PS</i>	4-249353	9/92	JAPAN					
<i>PS</i>	11-260979	09/99	JAPAN					
<i>PS</i>	4-27145	01/92	JAPAN					
<i>PS</i>	9-148492	06/97	JAPAN					
<i>PS</i>	4-12555	01/92	JAPAN					
<i>PS</i>	4-103150	04/92	JAPAN					
<i>PS</i>	60-137042	07/85	JAPAN					
<i>PS</i>	5-109919	04/93	JAPAN					
<i>PS</i>	61-166051	07/86	JAPAN					
<i>PS</i>	2-117157	05/90	JAPAN					
<i>PS</i>	63-102326	05/88	JAPAN					

## OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, etc.)

EXAMINER	<i>Ryan</i>	DATE CONSIDERED	8/11/05
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## U.S. PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS
<i>RP</i>	5,990,550	Nov. 23, 1999	Umezawa		
<i>RP</i>	5,608,610	Mar. 4, 1997	Brzezinski		
<i>RP</i>	5,396,403	Mar. 7, 1995	Patel		
<i>RP</i>	5,293,301	Mar. 8, 1994	Tanaka et al.		
<i>RP</i>	5,641,997	June 24, 1997	Ohta et al.		
<i>RP</i>	5,789,820	Aug. 4, 1998	Yamashita		

## FOREIGN PATENT DOCUMENTS

								TRANSLATION	
		DOCUMENT NUMBER	DATE	COUNTRY	NAME	CLASS	SUB CLASS	YES	NO
RP		60-235430	11/85	JAPAN					
RP		07-240432	9/95	JAPAN					
RP		8-45874	2/96	JAPAN					
RP		60-95947	05/85	JAPAN					
RP		61-265849	11/86	JAPAN					
RP		62-141751	06/87	JAPAN					
RP		63-096946	04/88	JAPAN					
RP		62-92349	4/87	JAPAN					
RP		62-287649	12/87	JAPAN					
RP		59-38734	09/84	JAPAN					
RP		01-228138	09/89	JAPAN					
RP		54-40569	03/79	JAPAN					
RP		61-251043	11/86	JAPAN					
RP		54-95183	07/79	JAPAN					

## OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, etc.)

EXAMINER	<i>K. RP</i>	DATE CONSIDERED <i>8/11/05</i>

FORM PTO-1449	ATTY. DKT NO.	1-103-CON3	SER. NO.
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## REFERENCE DESIGNATION

## U.S. PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS
<i>DS</i>	2002/0158333	Oct. 31, 2002	Teshima		
<i>DS</i>	S/N 10/201556	July 24, 2002	Hirano et al.		
<i>DS</i>	5726466	March 10, 1998	Nishitani		
<i>DS</i>	4,470,063	Sep. 4, 1984	Arakawa et al.		
<i>DS</i>	5,708,299	Jan. 13, 1998	Teramae et al		

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## TRANSLATION

	DOCUMENT NUMBER	DATE	COUNTRY	NAME	CLASS	SUB CLASS	YES	NO
<i>DS</i>	59-031042	02/84	JAPAN					
<i>DS</i>	07-038013	02/95	JAPAN					
<i>DS</i>	07-273276	10/95	JAPAN					
<i>DS</i>	08-191145	07/96	JAPAN					
<i>DS</i>	2000-91485	03/00	JAPAN					
<i>DS</i>	W098/12748	3/26/98	PCT					
<i>DS</i>	JP-A-5-283562 *	10/29/93	JAPAN				X	
<i>DS</i>	JP-A-6-349987 *	12/22/94	JAPAN				X	
<i>DS</i>	JP-A-7-45765 *	2/14/95	JAPAN				X	
<i>DS</i>	JP-A-11-186469 *	7/9/99	JAPAN				X	
<i>DS</i>	JP-A-2000-31351 *	1/28/00	JAPAN				X	
<i>DS</i>	JP-A-2001-118961 *	4/27/01	JAPAN				X	

## OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, etc.)

EXAMINER	<i>[Signature]</i>	DATE CONSIDERED <i>8/11/05</i>